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# Thermoelectric properties of $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$ oxyselenides†

 Aleksandra Khanina,<sup>a\*</sup> Andrei Novitskii,<sup>b</sup> Daria Pashkova,<sup>b</sup> Andrei Voronin,<sup>a</sup>  
 Takao Mori<sup>b,c</sup> and Vladimir Khovaylo<sup>\*ad</sup>

In this work,  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) compounds were synthesized by a solid state reaction followed by spark plasma sintering. The effect of simultaneous Bi to Pb substitution and Cu vacancy introduction on thermoelectric properties was investigated systematically. The power factor was significantly enhanced, contributing to the increase in the  $zT$  value. As a result, the  $zT_{\text{max}}$  of 0.75 at 773 K was obtained for the  $\text{Bi}_{0.94}\text{Pb}_{0.06}\text{Cu}_{0.94}\text{SeO}$  sample. To reveal the factors constraining the  $zT_{\text{max}}$  of  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$ -based oxyselenides, a further careful analysis of literature data was performed. We highlighted that for Pb-doped oxyselenides, the power factor is almost independent of the synthesis technique, while the lattice thermal conductivity is the main property determining  $zT_{\text{max}}$  and is highly affected by the synthesis method.

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## Introduction

Over the past few decades, global energy consumption has dramatically increased, with about two-thirds of produced energy being lost as waste heat. Therefore, technologies capable of efficiently recovering this heat are crucial for achieving sustainable development goals. In this context, thermoelectric materials, which enable the direct conversion of waste heat into electricity, have attracted significant attention from the scientific community.<sup>1</sup> The efficiency of thermoelectric energy conversion depends on the material's transport properties and is determined by the thermoelectric figure of merit  $zT = \alpha^2 \sigma T / \kappa_{\text{tot}}$ , where  $\alpha$ ,  $\sigma$ ,  $T$ , and  $\kappa_{\text{tot}}$  represent the Seebeck coefficient, electrical conductivity, absolute temperature, and total thermal conductivity, respectively.<sup>2</sup>

Currently, p-type BiCuSeO-based oxyselenides are among the most efficient oxygen-containing thermoelectric materials.<sup>3</sup> BiCuSeO crystallizes in a tetragonal layered ZrCuSiAs structure type with a  $P4/mmm$  space group and two formula units per unit cell. The crystal structure consists of alternately stacked insulating

$(\text{Bi}_2\text{O}_2)^{2+}$  layers (so-called “charge reservoir” layers) and conducting  $(\text{Cu}_2\text{Se}_2)^{2-}$  layers along the  $c$ -axis.<sup>4,5</sup> These BiCuSeO-based oxyselenides have drawn interest as thermoelectric materials, primarily due to their intrinsically low thermal conductivity, not exceeding  $1.5 \text{ W m}^{-1} \text{ K}^{-1}$  at room temperature, coupled with a relatively high Seebeck coefficient.<sup>6</sup> The main purpose of enhancing the  $zT$  of BiCuSeO is to optimize the charge carrier concentration  $n$ , which significantly boosts the power factor ( $\alpha^2 \sigma$ ) by balancing  $\alpha$  and  $\sigma$  values. Employing this approach in BiCuSeO-based oxyselenides has yielded  $zT_{\text{max}} > 1.2$  at  $T \geq 773 \text{ K}$ , achieved through the substitution of bismuth with various elements.<sup>7,8</sup>

However, as identified by Ioffe over six decades ago, an efficient thermoelectric material requires not only an optimal charge concentration  $n_{\text{opt}}$ , but also a maximized ratio of charge carrier mobility  $\mu$  to lattice thermal conductivity  $\kappa_{\text{lat}}$ , as this determines the  $zT_{\text{max}}$  achievable at a given temperature and charge carrier concentration.<sup>2</sup> While optimizing charge carrier concentration in BiCuSeO is feasible through heterovalent Bi substitution, methods to maximize  $\mu/\kappa_{\text{lat}}$  are less straightforward. In this context, it is important to consider the native defect chemistry of p-type BiCuSeO oxyselenides. In particular, copper vacancies ( $V_{\text{Cu}}$ ) identified as the predominant defect in BiCuSeO are responsible for its native p-type self-doping.<sup>9,10</sup> Moreover, the introduction of extra  $V_{\text{Cu}}$  promotes the carriers' delocalization between the charge reservoir and conducting layers,<sup>11,12</sup> which is beneficial for maintaining a high  $n/\mu$  ratio.<sup>13</sup> Although interlayer delocalization of carriers is favorable for interlayer charge transfer, conventional Bi substitution is still necessary to provide a sufficient number of charge carriers for diffusion.<sup>14</sup> For this purpose, it makes sense to

<sup>a</sup> Academic Research Center for Energy Efficiency, National University of Science and Technology MISIS, Leninsky Av. 4, Moscow, 119049, Russia.  
 E-mail: khanina.as@misis.ru, khovaylo@misis.ru

<sup>b</sup> International Center for Materials Nanoarchitectonics (WPI-MANA), National Institute for Materials Science (NIMS), 1-1 Namiki, Tsukuba, Ibaraki, 305-0044, Japan

<sup>c</sup> Graduate School of Pure and Applied Sciences, University of Tsukuba, 1-1-1 Tennodai, Tsukuba, Ibaraki, 305-8573, Japan

<sup>d</sup> Belgorod State University, Pobedy St. 85, Belgorod, 308015, Russia

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use the most efficient dopant, Pb,<sup>15</sup> which allows one to achieve the highest ratio of the nominal to actual number of introduced charge carriers per atom.

In our study, we synthesized a series of samples with the nominal composition of  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) to achieve simultaneous optimization of charge carrier concentration while maintaining high values of charge carrier mobility by combining the substitution of bismuth with lead ( $\text{Pb}_{\text{Bi}}$ ) and introducing extra copper vacancies ( $V_{\text{Cu}}$ ).  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$ -based oxyselenides are among the most studied compounds, and the influence of Bi to Pb substitution on transport properties has been thoroughly investigated. We demonstrated that the key factor affecting the thermoelectric performance of Pb-doped BiCuSeO and the variability reported in  $zT_{\text{max}}$  values is, in fact, the  $\mu_w/\kappa_{\text{lat}}$  ratio. At the same time, the power factor is predominantly influenced by the  $\text{Pb}_{\text{Bi}}$  concentration and is weakly dependent on the concentration of vacancies and/or the second dopant. Ultimately, we observed an almost fourfold increase in the power factor for  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  with  $x = 0.06$  and  $0.08$  at  $773$  K. The  $\mu_w/\kappa_{\text{lat}}$  ratio doubled with an increase from  $x = 0$  to  $x = 0.02$ ; however, a further increase in  $x$  did not yield an increase in  $\mu_w/\kappa_{\text{lat}}$  mainly due to the increase in  $\kappa_{\text{lat}}$  for  $x > 0.02$ . Ultimately, a notable increase in  $zT$  by a factor of three was realized, and  $zT_{\text{max}} = 0.75$  at  $773$  K for  $\text{Bi}_{0.94}\text{Pb}_{0.06}\text{Cu}_{0.94}\text{SeO}$  was achieved.

## Materials and methods

Compounds with the nominal chemical compositions of  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) were synthesized as reported elsewhere<sup>16</sup> using high purity CuO, Bi, Se, and PbO powders as the raw materials. The obtained products were consolidated through spark plasma sintering (SPS) at  $903$  K for  $5$  min under an axial pressure of  $50$  MPa. Phase composition analysis was carried out through powder X-ray diffraction (PXRD) using a DRON-3 diffractometer (IC Bourevestnik, Russia) with  $\text{Cu-K}\alpha$  radiation ( $\lambda = 1.54178$  Å). The PXRD patterns were refined by the Rietveld method with the self-developed software package.<sup>17</sup> Scanning electron microscopy (SEM) and energy-dispersive X-ray spectroscopy (EDS) were performed using a Vega 3SB SEM (Tescan, Czech Republic) equipped with an x-act EDS detector (Oxford Instruments, UK). The thermal diffusivity  $\chi$  was measured in the axial direction of disk-shaped samples of  $\phi 10 \times 1$  mm<sup>2</sup> using a laser flash analyzer (LFA 467 Hyperflash, Netzsch, Germany). The total thermal conductivity  $\kappa_{\text{tot}}$  was calculated using the formula  $\kappa_{\text{tot}} = \chi C_p d$ , where  $C_p$  represents the specific heat capacity, which was estimated using the comparison method (with Pyroceram-9060 as a reference sample) and is in good agreement with the  $C_p$  value calculated by the Debye model. The density  $d$  was determined using the Archimedes method. The Seebeck coefficient  $\alpha$  and the electrical conductivity  $\sigma$  were measured in the radial direction of bar-shaped specimens with dimensions of  $10 \times 3 \times 1$  mm<sup>3</sup> using a commercial apparatus (ZEM-3, Advance Riko Inc., Japan) under a partial He atmosphere from  $300$  to  $773$  K. The uncertainty in  $\sigma$

and  $\alpha$  was  $5\%$  and  $4\%$ , respectively, along with  $8\%$  in  $\kappa_{\text{tot}}$ . The overall uncertainty in  $zT$  was estimated to be less than  $17\%$ . The error bars are not shown for clarity and to enhance the visual representation of the figures.

## Results and discussion

The PXRD patterns of  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples are presented in Fig. 1a. All major reflections can be indexed to the tetragonal BiCuSeO phase (PDF#01-076-6689) with a ZrCuSiAs structure type and  $P4/mmm$  space group. A minor amount of the  $\text{Bi}_2\text{O}_3$  (PDF#01-088-2043) secondary phase ( $\leq 4.5$  vol%) was detected in all the samples, indicating significant Cu deficiency as expected.<sup>9,10,13,18</sup>

In the case of dual doping, the evolution of lattice parameters can be affected by two competing factors. On the one hand, Cu deficiency tends to decrease both lattice parameters  $a$  and  $c$ ,<sup>13</sup> while on the other hand, a larger ionic radius of  $\text{Pb}^{2+}$  ( $1.19$  Å) as compared to that of  $\text{Bi}^{3+}$  ( $1.03$  Å)<sup>19</sup> should result in an increase of lattice parameters.<sup>20,21</sup> Our experimental results reveal that, even with a simultaneous increase in the concentration of  $\text{Pb}_{\text{Bi}}$  and  $V_{\text{Cu}}$ , both lattice parameters  $a$  and  $c$  exhibit a gradual increase (Fig. 1b), resulting in the expansion of the unit cell volume. However, it is noteworthy that the effect of copper vacancies is noticeable, and for samples with the same nominal

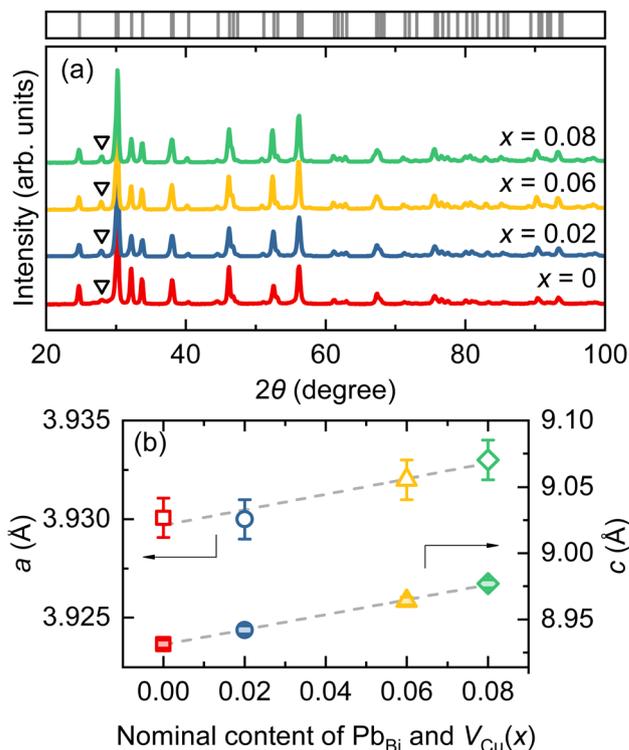


Fig. 1 (a) Powder XRD patterns of the  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples. Bragg reflections for the BiCuSeO phase are indicated by gray ticks on the top part of the figure. Diffraction peak corresponding to the  $\text{Bi}_2\text{O}_3$  secondary phase is indicated by a black triangle ( $\nabla$ ). (b) Lattice parameters ( $a$  and  $c$ ) as a function of nominal concentration of  $\text{Pb}_{\text{Bi}}$  and  $V_{\text{Cu}}$ .

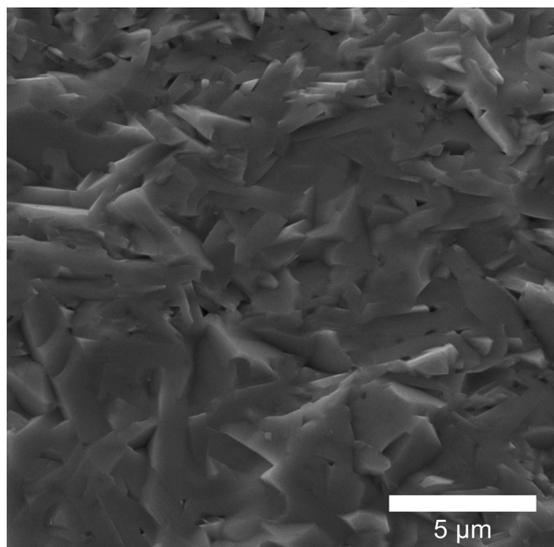


Fig. 2 SEM micrograph of the fractured cross-section of the  $\text{Bi}_{0.94}\text{Pb}_{0.06}\text{Cu}_{0.94}\text{SeO}$  sample.

concentration  $x$ , the lattice parameters of dually doped specimens are slightly smaller than those of the single Pb-doped ones.<sup>20–22</sup>

Fig. 2 displays a SEM micrograph, providing an overview of the microstructure representative of all samples. Randomly arranged platelet grains are stacked densely, which is reflected in the high relative densities of all samples ( $\geq 95\%$  of theoretical density). The thickness of the grains ranges from 300 to

600 nm. EDS analysis confirms that the actual compositions of the samples closely align with the nominal ones (Table S1, ESI<sup>†</sup>).

Fig. 3a shows the temperature dependence of electrical conductivity  $\sigma$  of  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples. For all the samples,  $\sigma$  gradually decreases with the increase of temperature, exhibiting a metal-like behavior as expected for heavily doped semiconductors.<sup>23</sup> As the content of  $\text{Pb}_{\text{Bi}}$  and  $V_{\text{Cu}}$  increases from 0 to 0.08,  $\sigma$  is vastly improved from  $\sim 30 \Omega^{-1} \text{ cm}^{-1}$  for the pristine  $\text{BiCuSeO}$  sample to  $\sim 450 \Omega^{-1} \text{ cm}^{-1}$  for  $\text{Bi}_{0.92}\text{Pb}_{0.08}\text{Cu}_{0.92}\text{SeO}$  at room temperature. Considering only a slight improvement in the weighted mobility  $\mu_w$  ( $\mu_w \approx \mu(m_d^*/m_e)^{3/2}$ , where  $m_d^*$  is the density of states effective mass and  $m_e$  is the electron mass) as shown in Fig. S1 (ESI<sup>†</sup>), the main reason for such a significant enhancement of the electrical conductivity is due to the increase in the charge carrier concentration, which is also in agreement with previous reports.<sup>22,24</sup> Furthermore, the carrier density increase originates mostly from the substitution of  $\text{Bi}^{3+}$  with  $\text{Pb}^{2+}$ , as even introducing only dual vacancies  $V_{\text{Bi}}$  and  $V_{\text{Cu}}$  in  $\text{BiCuSeO}$  led to an order of magnitude lower conductivity in comparison with the Pb-substituted ones.<sup>12</sup> Nonetheless, as discussed in the Introduction section, the introduction of vacancies plays not a primary but a complementary role, leading to a more pronounced delocalization of charge carriers between the layers, thereby promoting interlayer charge transfer.<sup>14</sup> This, in turn, allows for the retention of higher charge carrier mobility values at the same level of charge carrier concentration (see Fig. 12 in ref. 15).

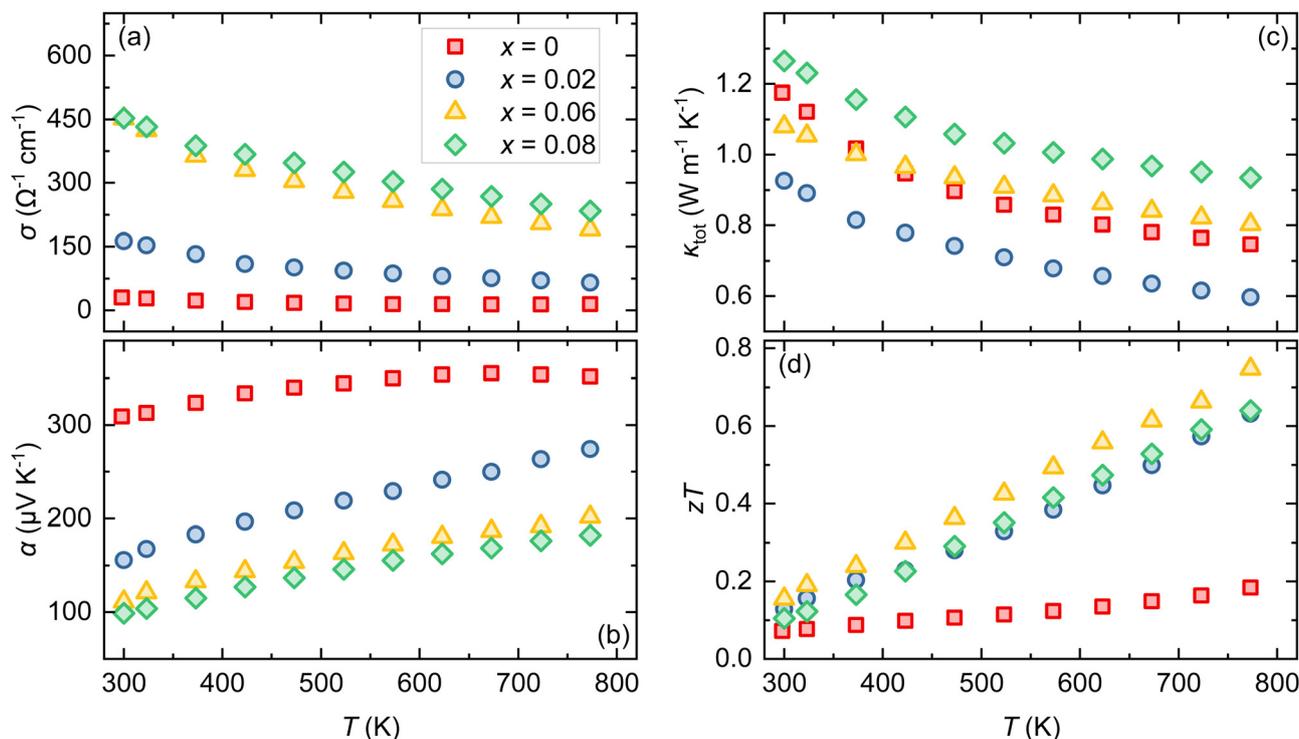


Fig. 3 Temperature dependence of the (a) electrical conductivity  $\sigma$ , (b) seebeck coefficient  $\alpha$ , (c) total thermal conductivity  $\kappa_{\text{tot}}$ , and (d) the figure of merit  $zT$  for  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples.

Fig. 3b illustrates the Seebeck coefficient  $\alpha$  as a function of temperature for  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples. The positive Seebeck coefficient for all samples in the entire temperature range confirms p-type conduction, indicating that holes are the majority charge carriers. The highest Seebeck coefficient throughout the investigated temperature range is observed in nominally undoped  $\text{BiCuSeO}$ . However, with the increase in  $\text{Pb}_{\text{Bi}}$  and  $V_{\text{Cu}}$  concentration,  $\alpha$  gradually decreases consistently with the changes in  $\sigma$  (Fig. S2, ESI<sup>†</sup>). Considering the relationship between the Seebeck coefficient and carrier concentration in semiconductors,<sup>2</sup> such a simultaneous change in electrical conductivity and the Seebeck coefficient further underscores that it is primarily driven by a significant increase in charge carrier concentration, as was discussed previously. Consequently, at 773 K,  $\alpha$  reduced from  $352 \mu\text{V K}^{-1}$  for  $x = 0$  to  $182 \mu\text{V K}^{-1}$  for  $x = 0.08$ . The achieved optimal balance between  $\sigma$  and  $\alpha$  results in a significant enhancement in the power factor ( $\alpha^2\sigma$ ), showing more than a fourfold increase at 773 K, from  $1.8 \mu\text{W cm}^{-1} \text{K}^{-2}$  to  $7.7 \mu\text{W cm}^{-1} \text{K}^{-2}$ , as the  $\text{Pb}_{\text{Bi}}$  and  $V_{\text{Cu}}$  content is raised from  $x = 0$  to 0.08 (Fig. 4a and Fig. S3, ESI<sup>†</sup>).

Fig. 3c shows the temperature-dependent total thermal conductivity  $\kappa_{\text{tot}}(T)$  of  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples. For pristine  $\text{BiCuSeO}$ ,  $\kappa_{\text{tot}}$  decreases from  $1.17 \text{ W m}^{-1} \text{K}^{-1}$  at 300 K to  $0.75 \text{ W m}^{-1} \text{K}^{-1}$  at 773 K. Following simultaneous Bi to Pb substitution and Cu vacancy introduction,  $\kappa_{\text{tot}}$  initially decreases ( $x = 0.02$ ) and then rises to  $0.93 \text{ W m}^{-1} \text{K}^{-1}$  at 773 K ( $x = 0.08$ ). This can be understood by considering the evolution of both the lattice  $\kappa_{\text{lat}}$  and electronic  $\kappa_{\text{el}}$  components of

total thermal conductivity. The  $\kappa_{\text{lat}}$  is calculated from  $\kappa_{\text{lat}} = \kappa_{\text{tot}} - \kappa_{\text{el}}$ , where  $\kappa_{\text{el}}$  can be determined through the Wiedemann–Franz law, expressed as  $\kappa_{\text{el}} = L\sigma T$ , with  $L$  representing the Lorentz number.<sup>2</sup> The Lorentz number is estimated with sufficient accuracy within the single parabolic band model with acoustic phonon scattering from experimental  $\alpha$  values as  $L = 1.5 + \exp\{-|\alpha|/116\}$ .<sup>25</sup> Owing to a significant enhancement in  $\sigma$ , the changes in  $\kappa_{\text{tot}}$  become more apparent. In pristine  $\text{BiCuSeO}$ ,  $\kappa_{\text{el}}$  contributes to approximately 2% of the total, but this contribution rises up to over 30% with an increase in  $\text{Pb}_{\text{Bi}}$  and  $V_{\text{Cu}}$  concentration (Fig. S4, ESI<sup>†</sup>). Analysis of the  $\kappa_{\text{lat}}(T)$  reveals that point defects are the dominant phonon scattering mechanism, evidenced by a decrease of  $\kappa_{\text{lat}}$  with temperature as  $T^{-0.5}$  for all the samples (Fig. S5, ESI<sup>†</sup>). However, for the samples with  $x > 0.02$   $\kappa_{\text{lat}}$  slightly increases but still remains lower than that of pristine  $\text{BiCuSeO}$ . This increase could be attributed to an increase in the grain size, sound velocities, and/or Pb–O bond strength due to the introduction of  $\text{Pb}_{\text{Bi}}$  and  $V_{\text{Cu}}$ .<sup>26</sup>

Combining the electrical and thermal transport properties, the figure of merit  $zT$  as a function of temperature is calculated and displayed in Fig. 3d. For  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  samples ( $x > 0$ ), the  $zT$  values are enhanced over the entire test temperature range by more than 3 times. This improvement is mainly attributed to a significant boost in the power factor, leading to a  $zT_{\text{max}}$  value of 0.75 at 773 K for  $\text{Bi}_{0.94}\text{Pb}_{0.06}\text{Cu}_{0.94}\text{SeO}$ . On the one hand, a nearly threefold increase in  $zT$  was achieved compared to undoped  $\text{BiCuSeO}$ . On the other hand, we must admit that this is not the highest  $zT$  value achieved for  $\text{Bi}_{1-x}\text{Pb}_x\text{CuSeO}$ -based oxyselenides. Furthermore, a detailed analysis of literature data reveals that reported  $zT$  values for Pb-doped  $\text{BiCuSeO}$  are scattered between 0.56 and 1.05 at  $T = 773 \text{ K}$  for optimally doped compositions (Fig. S6, ESI<sup>†</sup>).

To understand what causes such a discrepancy in  $zT$  values, we analyzed the literature and our data within the concept proposed by Ioffe and later reformulated by Chasmar and Stratton.<sup>2,27</sup> an efficient thermoelectric material should have (1) an optimal charge carrier concentration and (2) a maximized  $\mu_{\text{w}}/\kappa_{\text{lat}}$  ratio, where  $\mu_{\text{w}}$  and  $\kappa_{\text{lat}}$  are the weighted mobility and lattice thermal conductivity, respectively. This ratio determines the maximum  $zT$  value achievable for a given material at a given temperature.<sup>28</sup> Thus, one can notice that the achieved power factor ( $\alpha^2\sigma$ ) for optimally doped samples ( $\ln\sigma \approx 2.3$ ) was around  $8 \text{ W cm}^{-1} \text{K}^{-2}$  at 773 K and was roughly the same compared to those reported previously for other Pb-doped  $\text{BiCuSeO}$  oxyselenides (Fig. 4a). In other words, regardless of the synthesis method, the optimal level of charge carrier concentration in  $\text{Bi}_{1-x}\text{Pb}_x\text{CuSeO}$ -based oxyselenides is reached around  $\ln\sigma = 2.3$ , corresponding to the Pb doping level  $x$  between 0.06 and 0.08. However, the  $\mu_{\text{w}}/\kappa_{\text{lat}}$  ratio, on the other hand, is strongly affected by the synthesis technique (Fig. 4b). The highest values of  $\mu_{\text{w}}/\kappa_{\text{lat}}$  are achieved for the samples synthesized/processed by techniques such as shear exfoliation,<sup>29</sup> high-energy ball milling,<sup>18</sup> self-propagating high-temperature synthesis,<sup>30,31</sup> etc. In such samples, lattice thermal conductivity is suppressed by about twice compared to the glassy limit ( $\approx 0.59 \text{ W m}^{-1} \text{K}^{-1}$ ) at high temperature. This originates from increased phonon scattering

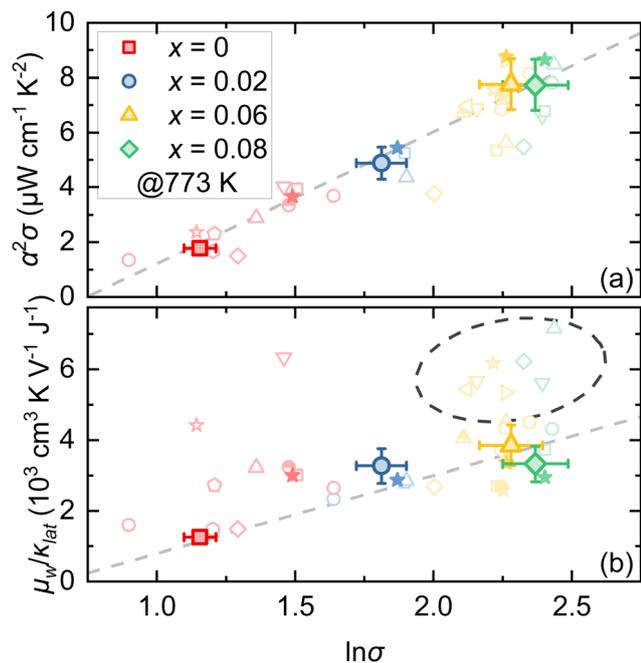


Fig. 4 (a) Power factor  $\alpha^2\sigma$  and (b)  $\mu_{\text{w}}/\kappa_{\text{lat}}$  ratio as a function of  $\ln\sigma$  for the  $\text{Bi}_{1-x}\text{Pb}_x\text{Cu}_{1-x}\text{SeO}$  ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples. Literature data for other  $\text{Bi}_{1-x}\text{Pb}_x\text{CuSeO}$ -based oxyselenides are also shown for comparison (Chen *et al.*,<sup>24</sup> Gu *et al.*,<sup>29,32</sup> Lan *et al.*,<sup>18</sup> Lei *et al.*,<sup>33</sup> Li *et al.*,<sup>34</sup> Liang *et al.*,<sup>35</sup> Liu *et al.*,<sup>36</sup> Pan *et al.*,<sup>37</sup> Ren *et al.*,<sup>30,31</sup> Xu *et al.*,<sup>38</sup> and Zhu *et al.*<sup>14</sup>). All displayed data points correspond to values obtained at 773 K.

induced by the significantly reduced grain size<sup>29</sup> and, what is more important, introduced crystal defects, such as nanodots,<sup>18</sup> amorphous regions,<sup>30,31</sup> *etc.* Thus, the abovementioned findings highlight the importance of the microstructure (grain size and shape, defects, *etc.*) in the thermoelectric performance of Pb-doped BiCuSeO oxyselenides.

## Conclusions

The thermoelectric properties of the Bi<sub>1-x</sub>Pb<sub>x</sub>Cu<sub>1-x</sub>SeO ( $x = 0, 0.02, 0.06, \text{ and } 0.08$ ) samples prepared *via* a solid-state reaction route followed by spark plasma sintering have been studied. The combination of Pb for Bi substitution and Cu vacancy introduction increases the electrical conductivity while moderately decreasing the Seebeck coefficient. The intrinsically low thermal conductivity of BiCuSeO is noticeably decreased by the introduction of a low concentration ( $x = 0.02$ ) of Pb<sub>Bi</sub> and V<sub>Cu</sub> and increased with a further increase in  $x$ . The optimum balance between the Seebeck coefficient and electrical conductivity was achieved for  $x = 0.06$ , while for  $x > 0.02$ , the  $\mu_w/\kappa_{\text{lat}}$  ratio essentially does not increase and remains at the same level as for  $x = 0.02$ , limiting the potentially achievable  $zT_{\text{max}}$ . As a result, the value of  $zT$  was eventually increased by more than 3 times compared to the undoped BiCuSeO, and  $zT_{\text{max}} = 0.75$  at 773 K was achieved for Bi<sub>0.94</sub>Pb<sub>0.06</sub>Cu<sub>0.94</sub>SeO. By careful analysis of the literature data and comparing them with our results, we revealed that for Bi<sub>1-x</sub>Pb<sub>x</sub>CuSeO-based oxyselenides, the main factor determining  $zT_{\text{max}}$  is the  $\kappa_{\text{lat}}$ . We believe that highlighting the mechanisms determining the  $zT$  value of doped BiCuSeO will help future researchers to develop more effective synthesis/doping strategies.

## Author contributions

Aleksandra Khanina: investigation, formal analysis, visualization, writing – original draft, writing – reviewing and editing; Andrei Novitskii: conceptualization, formal analysis, investigation, methodology, visualization, writing – original draft, writing – reviewing and editing; Daria Pashkova: data curation, investigation, formal analysis, visualization; Andrei Voronin: project administration, funding acquisition; Takao Mori: resources, funding acquisition, supervision, writing – reviewing and editing; and Vladimir Khovaylo: resources, supervision, writing – reviewing and editing.

## Conflicts of interest

There are no conflicts to declare.

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